



Search Result - Print Format

Key: IEEE JNL = IEEE Journal or Magazine, IEE JNL = IEE Journal or Magazine, AIF JNL = AIF JNL = AVS JNL, IEEE CNF = IEEE Conference, IEE CNF = IEE Conference, IEEE STD = IEEE

1. Detection of Surface Cleanliness Based on Image Recognition

Huang Yanyan; Gao Na; Yu Ming; Zhao Xiaoan;
Intelligent Information Technology Application, 2008. IITA '08. Second International Symposium
Volume 2, 20-22 Dec. 2008 Page(s):360 - 365

IEEE CNF

2. Research and Development of Intelligent and Automatic Detective System on Hole Surface

Yang Musheng; Zhang Yu; Wang Huilin;
Intelligent Computation Technology and Automation, 2009. ICICTA '09. Second International Conference
Volume 2, 10-11 Oct. 2009 Page(s):399 - 402

IEEE CNF

3. Visual quality recognition of nonwovens based on wavelet transform and LVQ neural network

Jianli Liu; Baoqi Zuo; Vroman, P.; Rabenasolo, B.; Xianyi Zeng;
Computers & Industrial Engineering, 2009. CIE 2009. International Conference on
6-9 July 2009 Page(s):1885 - 1890

IEEE CNF

4. Application of a New Image Recognition Technology in Fabric Defect Detection

Bo Cui; Haiying Liu; Tongze Xue;
Future BioMedical Information Engineering, 2008. FBIE '08. International Seminar on
18-18 Dec. 2008 Page(s):67 - 70

IEEE CNF

5. Automatic image processing filter generation for visual defects classification system

Hata, S.; Hayashi, J.;
Mechatronics, 2009. ICM 2009. IEEE International Conference on
14-17 April 2009 Page(s):1 - 6

IEEE CNF

6. Research on the recognition of surface defects in copper strip based on fuzzy neural network

Xue-wu Zhang; Yan-yun Lv; Yan-qiong Ding; Zhen-tao Zhou;
Cybernetics and Intelligent Systems, 2008 IEEE Conference on
21-24 Sept. 2008 Page(s):1151 - 1154

IEEE CNF

7. A new approach for automatic quality control of fried potatoes using machine learning

Lotfi, E.; Yaghoobi, M.; Pourreza, H.R.;
Cybernetic Intelligent Systems, 2008. CIS 2008. 7th IEEE International Conference on
9-10 Sept. 2008 Page(s):1 - 4

IEEE CNF

8. Pattern recognition for infrared profiles of steel strips based on fuzzy knowledge

Usamentiaga, R.; Garcia, D.F.; Gonzalez, D.; Molleda, J.;
Computational Intelligence for Measurement Systems and Applications, Proceedings of 2006 IEEE
Conference on
12-14 July 2006 Page(s):122 - 127

IEEE CNF

9. **Automatic Image Processing Filter Creation System Using NN**
Hata, S.; Tanaka, T.; Iga, T.; Nakamura, T.;
Industrial Electronics, 2007. ISIE 2007. IEEE International Symposium on
4-7 June 2007 Page(s):1569 - 1573
IEEE CONF
10. **The development of an artificial neural network embedded automated inspection quality**
Chih-Hsien Kung; Devaney, M.J.; Chung-Ming Huang; Chih-Ming Kung; Yi-Jen Wang;
Instrumentation and Measurement Technology Conference, 2001. IMTC 2001. Proceedings of the
Volume 2, 21-23 May 2001 Page(s):865 - 868 vol.2
IEEE CONF
11. **Graphics file generation for a computer-aided manual work station in the electronics manufacturing environment**
Hilde, A.R.; Rath, H.;
Electronic Manufacturing Technology Symposium, 1993, Fifteenth IEEE/CHMT International
4-6 Oct. 1993 Page(s):362 - 367
IEEE CONF

